

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components, Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Conformity Approved Process

IECQ Certificate No.: IECQ-P ULTW 16.0003-02

CB Certificate No.: T1107-2

Schedule Number: IECQ-P ULTW 16.0003-02-S Rev No.: 1 Revision Date: 2018/09/20 Page 1 of 3

Appendix-1 (T1107-2) Schedule of Scope to Certificate of Approval

| Description test | Standard | Remarks |
|------------------|------------------|-------------------------|
| SEM | T-SEM-3 | By customer requirement |
| TEM-EELS | Т-ТЕМ-3 | By customer requirement |
| EDS | T-SEM-3, T-TEM-3 | By customer requirement |
| FIB | T-FIB-3 | By customer requirement |
| Liquid Cell | Т-ТЕМ-3 | By customer requirement |
| SIMS | T-SIM-3 | By customer requirement |
| AFM | T-SIM-3 | By customer requirement |
| SRP | T-SIM-3 | By customer requirement |
| Alpha step | T-SIM-3 | By customer requirement |
| XRD | T-SIM-3 | By customer requirement |
| XPS | T-SIM-3 | By customer requirement |
| X-Ray | T-EFA-3 | By customer requirement |
| ЕММІ | T-EFA-3 | By customer requirement |
| EMMI-InGaAs | T-EFA-3 | By customer requirement |

This schedule is only valid in conjunction with the referenced Certificate of Approval
This approval and any schedule(s) may only be reproduced in full.
This approval is not transferable and remains the property of the issuing body.
The Status and authenticity of this approval and any schedule(s) may be verified by visiting the
Official IECQ Website. www.iecq.org





IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components, Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Conformity Approved Process

IECQ Certificate No.: IECQ-P ULTW 16.0003-02

CB Certificate No.: T1107-2

Schedule Number: IECQ-P ULTW 16.0003-02-S Rev No.: 1 Revision Date: 2018/09/20 Page 2 of 3

| OBIRCH | T-EFA-3 | By customer requirement |
|------------------------------|---------------|----------------------------|
| C-AFM | T-EFA-3 | By customer requirement |
| SCM | T-SIM-3 | By customer requirement |
| Scanning Acoustic Tomography | T-EFA-3 | By customer requirement |
| Optical Microscope | T-OMI-3 | By customer requirement |
| 3D Optical Microscope | T-LAB-3 | By customer requirement |
| Optical Profiler | T-SIM-3 | By customer requirement |
| IC Layout Imaging | T-OMI-3 | By customer requirement |
| Circuitry analysis | T-OMI-3 | By customer requirement |
| Auger | T-SIM-3 | By customer requirement |
| THEMOS | T-EFA-3 | By customer requirement |
| Latch-up | JEDEC78 | Or customer specified test |
| нвм | JS-001 | Or customer specified test |
| ММ | JS-001 | Or customer specified test |
| CDM | JS-002 | Or customer specified test |
| ESD Gun | IEC 61000-4-2 | Or customer specified test |
| TLP | ESDA | Or customer specified test |

This schedule is only valid in conjunction with the referenced Certificate of Approval
This approval and any schedule(s) may only be reproduced in full.
This approval is not transferable and remains the property of the issuing body.
The Status and authenticity of this approval and any schedule(s) may be verified by visiting the
Official IECQ Website. www.iecq.org





IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components, Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Conformity Approved Process

IECQ Certificate No.: IECQ-P ULTW 16.0003-02

CB Certificate No.: T1107-2

Schedule Number: IECQ-P ULTW 16.0003-02-S Rev No.: 1 Revision Date: 2018/09/20 Page 3 of 3

| EOS | IEC 61000-4-5 | Or customer specified test |
|---------------------|--|----------------------------|
| Wire Bonding | NA | By customer requirement |
| IC Package | NA | By customer requirement |
| Pull and shear test | MIL-STD-883J method 2011.9 MIL-STD-883J method 2023.7 AEC-Q100-001 EIA/JESD22-B116 JESD22-B117 | Or customer specified test |

| Technical Reviewer of DQS: | michael Chine | Date: Sep. 6, 2018 |
|----------------------------|---------------|---------------------|
| | Jae Lee | - |
| US-NAL ECCC T R C C sign: | | Date: Sep. 10, 2018 |



